

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/650,336	KAWA ET AL.	
Examiner	Art Unit	
Y. Lee	2621	

SEARCHED							
Class	Subclass	Date	Examiner				
375	240.01 240.13 240.21 240.25 **	1/11/2007	YL				
	240.26						
H04N	7/12						

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examine		

STRATEGY	7)
DATE	EXMR
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